## Notice of References Cited

Application/Control No.

Applicant(s)/Patent Under Reexamination
ANDIDEH ET AL.

Examiner

Art Unit

Examiner
George Fourson

Art Unit 2823

Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,159,845	12-2000	Yew et al.	438/637
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-	,		
	G	US-			
	Ξ	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	×						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.